

Resource Summary Report

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Gatan: Ilion II System Scanning Electron Microscope (SEM) Specimen Preparation

RRID:SCR_019934

Type: Tool

Proper Citation

Gatan: Ilion II System Scanning Electron Microscope (SEM) Specimen Preparation (RRID:SCR_019934)

Resource Information

URL: <https://www.gatan.com/products/sem-specimen-preparation/ilion-ii-system>

Proper Citation: Gatan: Ilion II System Scanning Electron Microscope (SEM) Specimen Preparation (RRID:SCR_019934)

Description: Microscope accessory that is used for low energy surface preparation for SEM cross section viewing.

Resource Type: instrument resource

Keywords: Gatan, SEM Specimen Preparation, Instrument Equipment, USEdit,

Availability: Commercially available

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/main/PDF/SCR_019934.pdf

Resource Name: Gatan: Ilion II System Scanning Electron Microscope (SEM) Specimen Preparation

Resource ID: SCR_019934

Alternate IDs: Model_Number_Ilion_II

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190635+0000

Ratings and Alerts

No rating or validation information has been found for Gatan: Ilion II System Scanning Electron Microscope (SEM) Specimen Preparation.

No alerts have been found for Gatan: Ilion II System Scanning Electron Microscope (SEM) Specimen Preparation.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.